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PATENT NUMBER and  
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## U.S. UTILITY Patent Application

APPL NUM	FILING DATE	CLASS	SUBCLASS	GAU	EXAMINER
10073129	02/13/2002	365	724	2810	Dekay

\*\*APPLICANTS: Sato Masahiro; Akaza Junji; Kodama Nobumi; Mizuno Hirohisa; Imura Takashi; Matsuzaki Yasuoru;

714 / 733 2133 TABONE

\*\*CONTINUING DATA VERIFIED:

\*\* FOREIGN APPLICATIONS VERIFIED:

JAPAN 2001-199188 06/29/2001

PG-PUB	DO NOT PUBLISH <input type="checkbox"/>	RESCIND <input type="checkbox"/>	
Foreign priority claimed 35 USC 119 conditions met		<input type="checkbox"/> yes <input type="checkbox"/> no	ATTORNEY DOCKET NO
Verified and Acknowledged Examiners's initials		<input type="checkbox"/> yes <input type="checkbox"/> no	108075-00075
TITLE : Test apparatus for semiconductor device			
U.S. DEPT. OF COMM./PAT. & TM-PTO-436L(Rev. 12-94)			

NOTICE OF ALLOWANCE MAILED		CLAIMS ALLOWED	
		Total Claims:	Print Claim for O.G.
Assistant Examiner		DRAWING	
		Sheets Drwg.	Figs.Drwg.
Primary Examiner		Print Fig.	
PREPARED FOR ISSUE		Application Examiner	
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